

Search Notes

Application/Control No.

10/566,604

Examiner

Hai H. Huynh

Applicant(s)/Patent under
Reexamination

MORIYA ET AL.

Art Unit

3747

SEARCHED

Class	Subclass	Date	Examiner
123	435-436	2/5/2007	HHH
73	118.1	2/5/2007	HHH
73	118.2	2/5/2007	HHH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
above	search	2/5/2007	HHH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	2/5/2007	HHH